

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination MIYASHITA ET AL.	
		Examiner Sudhanshu C. Pathak	Art Unit 2634	Page 1 of 1

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	B	US-6,541,950	04-2003	Townsend et al.	324/76.14
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	N	JP-A-09-247128	09-1997	Japan	Kuroda Toru et al.	H04L 1/00
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	De-skewing and comparing Waveforms; "www.lecroy.com/lm/library/LABs/LAB724/default.asp"; LeCroy, Digital Oscilloscopes; Technical Library; Lab Briefs; Pages 1-3.
	V	Making PRML Measurements with Digital Oscilloscopes; "www.lecroy.com/lm/library/AppNotes/PRMLMeas/default.asp"; LeCroy, Digital Oscilloscopes; Technical Library; Applications Notes; Pages 1-8.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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